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Ni-based superalloy: crystalline orientation mapping and $\gamma - \gamma'$ phases discrimination with the iCHORD method

C. Langlois$^1$, M-A. Charpagné$^2$, S. Vernier$^2$, S. Dubail$^3$, T. Douillard$^1$, N. Bozzolo$^2$

$^1$University of Lyon, MATEIS, univ CNRS 5510, Bât. B. Pascal, INSA de Lyon/Université Lyon 1, 69621 Villeurbanne Cedex, France
$^2$CEMEF – Mines ParisTech, univ CNRS 7635, CS 10207 rue Claude Daunesse 06904 Sophia Antipolis Cedex, France
$^3$AXON SQUARE SAS, 4 la Tuilière, 74140 SCIEZ, France

Ni-based superalloy: crystalline orientation mapping

Electron backscatter diffraction (EBSD) is routinely employed as a characterization tool to obtain individual grain orientations, local texture and phase identification. However, in the case of $\gamma - \gamma'$ Ni-based superalloys, the EBSD technique allows mapping the orientations but fails discriminating the two phases because their diffraction signature is too similar. A coupling with EDX analysis for instance helps to identify the two phases but suffers from the lack of spatial resolution of the EDX maps. Another way to discriminate the two phases is to use the BSE images, sensible to the chemistry, but because of the difference in the geometry of acquisition of the EBSD images and the BSE images, superposition of the two information is complicated by strong spatial distortions. In this context, any new technique that can lead to an easier phase and orientation mapping would be welcome, especially to resolve the fine secondary $\gamma'$ precipitates (typically few tens of nanometers).

How to efficiently discriminate between $\gamma$ matrix and $\gamma'$ precipitates in an orientation map?

Mixing EBSD, BSE and EDS maps: not convincing

The above figure shows the chemical and structural data that can be obtained on the same area of a Ni-based superalloy. The EBSD data (c) are obtained with a sample tilted to 70° whereas the BSE images (a) are obtained with the normal of the sample perpendicular to the incident electron beam. BSE and EBSD maps are therefore difficult to superimpose because of image distortions due to the different geometries of acquisition. Concerning EDS maps, the interaction volume is very large compared to the electron probe. The actual resolution of the EDS maps is then about 1 µm. This coarse spatial resolution prevents detecting the smallest $\gamma'$ precipitates in correlation to EBSD (b).

Orientation mapping using channeling

Here is a brief summary of the iCHORD technique, allowing obtaining orientation maps in a FIB microscope without the need of an EBSD camera.

1. Image acquisition

The sample is first tilted to an angle of 40°. Then, it is rotated around its tilted normal. For each rotation step, an image is acquired using the secondary electron detector. A complete 360° rotation is achieved, resulting in a series of ion images.

For a given orientation of a crystal (i.e. one grain in one image of the series), the intensity received by the detector from this crystal can be related to the projection of the atoms on a plane corresponding to the sample surface. More precisely, it is the sum of the grey levels of the pixels composing the projection that can be related to the intensity received, after some mathematical adjustments for the relative contribution of each atom in the projection. It constitutes one data point in an intensity profile. The orientation of the crystal is then changed in the same way as the experimental conditions, and the complete theoretical profile is obtained.

The database is then constructed by sampling the orientation space, and associating an intensity profile to each Euler triplet. As we are in a cubic system, the Euler angles vary in a range of $[0°, 360°]$ for $\varphi_1$ and $[0°, 90°]$ for $\varphi_2$ and $\varphi_3$ (Bunge convention).

The secondary electron detector used for the acquisition of images series can also be used to detect secondary ions, by changing its polarity. The resulting images present a strong contrast between $\gamma$ and $\gamma'$ phases, with also a bit of channeling contrast. To remove the channeling information, several images are acquired at different orientation (during the rotation series) and an average image is calculated. A threshold operation can then be applied to this average image, with no more channeling contrast.

On the image presented here, three families of $\gamma'$ precipitates are present with different size ranges. In the recrystallized area, large precipitates of 3-5 µm are visible near the grain boundaries as well as very small precipitates inside the grains. In the deformed area (in the center), precipitates with ~1µm diameter are visible.

2. Theoretical database construction

For a given orientation of a crystal (i.e. one grain in one image of the series), the intensity received by the detector from this crystal can be related to the projection of the atoms on a plane corresponding to the sample surface. More precisely, it is the sum of the grey levels of the pixels composing the projection that can be related to the intensity received, after some mathematical adjustments for the relative contribution of each atom in the projection. It constitutes one data point in an intensity profile. The orientation of the crystal is then changed in the same way as the experimental conditions, and the complete theoretical profile is obtained.

The database is then constructed by sampling the orientation space, and associating an intensity profile to each Euler triplet. As we are in a cubic system, the Euler angles vary in a range of $[0°, 360°]$ for $\varphi_1$ and $[0°, 90°]$ for $\varphi_2$ and $\varphi_3$ (Bunge convention). Euler angles are converted to quaternions for simplicity sakes in the computations.

The search in the database starts with some s brute force search for a certain amount of positions in the area. Then, an algorithm relying on similarities between the neighbouring profiles is used to index the pixels.

The size of the database increases the angular resolution but also the indexation time. However, it is possible to statistically evaluate the angular resolution obtained with a given database. It is then the user that choose which precision is required for a given application.

3. Database search

The search in the database starts with some s brute force search for a certain amount of positions in the area. Then, an algorithm relying on similarities between the neighbouring profiles is used to index the pixels.

The size of the database increases the angular resolution but also the indexation time. However, it is possible to statistically evaluate the angular resolution obtained with a given database. It is then the user that choose which precision is required for a given application.

Conclusion

Using the iCHORD method allows obtaining orientation maps with a very good spatial resolution on $\gamma - \gamma'$ sample (pixel size 0.14 µm). Mixing the orientation map with chemical information obtained with secondary ion images allows discriminating between the two phases, keeping the spatial resolution.

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